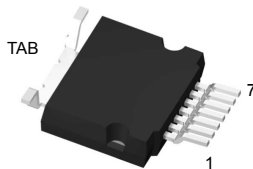
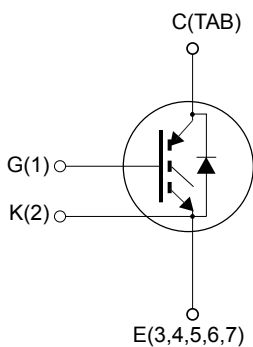


## Automotive-grade trench gate field-stop 650 V, 30 A low-loss M series IGBT in an HU3PAK package




HU3PAK



K2G1CTABE34567



### Features

- AEC-Q101 qualified 
- Maximum junction temperature:  $T_J = 175\text{ °C}$
- 6  $\mu\text{s}$  of minimum short-circuit withstand time
- $V_{CE(sat)} = 1.6\text{ V (typ.) @ } I_C = 30\text{ A}$
- Tight parameter distribution
- Safer paralleling
- Low thermal resistance
- Soft and very fast-recovery antiparallel diode
- Excellent switching performance thanks to the extra driving kelvin pin

### Applications

- Automotive motor control
- e-compressor
- Industrial motor control
- Power supplies and converters

### Description

This device is an IGBT developed using an advanced proprietary trench gate field-stop structure. The device is part of the M series IGBTs, which represent an optimal balance between inverter system performance and efficiency where the low-loss and the short-circuit functionality is essential. Furthermore, the positive  $V_{CE(sat)}$  temperature coefficient and the tight parameter distribution result in safer paralleling operation.

#### Product status link

[STGHU30M65DF2AG](#)

#### Product summary

Order code	STGHU30M65DF2AG
Marking	G30M65DF2AG
Package	HU3PAK
Packing	Tape and reel

# 1 Electrical ratings

**Table 1. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{CES}$	Collector-emitter voltage ( $V_{GE} = 0$ V)	650	V
$I_C$	Continuous collector current at $T_C = 25$ °C	84	A
	Continuous collector current at $T_C = 100$ °C	57	
$I_{CP}^{(1)}$	Pulsed collector current ( $t_p \leq 1$ $\mu$ s)	120	A
$V_{GE}$	Gate-emitter voltage	$\pm 20$	V
	Transient gate-emitter voltage ( $t_p \leq 10$ $\mu$ s, $D < 0.01$ )	$\pm 30$	
$I_F$	Continuous forward current at $T_C = 25$ °C	69	A
	Continuous forward current at $T_C = 100$ °C	43	
$I_{FP}^{(1)}$	Pulsed collector current ( $t_p \leq 1$ $\mu$ s)	120	A
$P_{TOT}$	Total power dissipation at $T_C = 25$ °C	441	W
$T_{STG}$	Storage temperature range	-55 to 150	°C
$T_J$	Operating junction temperature range	-55 to 175	°C

1. Defined by  $R_{thJC}$  and limited by maximum junction temperature, not tested in production.

**Table 2. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thJC}$	Thermal resistance, junction-to-case, IGBT	0.34	°C/W
	Thermal resistance, junction-to-case, diode	0.82	
$R_{thJA}$	Thermal resistance, junction-to-ambient	30	°C/W

## 2 Electrical characteristics

$T_J = 25\text{ °C}$  unless otherwise specified.

**Table 3. Static characteristics**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)CES}$	Collector-emitter breakdown voltage	$V_{GE} = 0\text{ V}$ , $I_C = 250\text{ }\mu\text{A}$	650			V
$V_{CE(sat)}$	Collector-emitter saturation voltage	$V_{GE} = 15\text{ V}$ , $I_C = 30\text{ A}$		1.60	2.0	V
		$V_{GE} = 15\text{ V}$ , $I_C = 30\text{ A}$ , $T_J = 125\text{ °C}$		1.84		
		$V_{GE} = 15\text{ V}$ , $I_C = 30\text{ A}$ , $T_J = 175\text{ °C}$		2.0		
$V_F$	Forward on-voltage	$I_F = 30\text{ A}$		1.86	2.65	V
		$I_F = 30\text{ A}$ , $T_J = 125\text{ °C}$		1.6		
		$I_F = 30\text{ A}$ , $T_J = 175\text{ °C}$		1.5		
$V_{GE(th)}$	Gate threshold voltage	$V_{CE} = V_{GE}$ , $I_C = 500\text{ }\mu\text{A}$	5	6	7	V
$I_{CES}$	Collector cut-off current	$V_{GE} = 0\text{ V}$ , $V_{CE} = 650\text{ V}$			25	$\mu\text{A}$
$I_{GES}$	Gate-emitter leakage current	$V_{CE} = 0\text{ V}$ , $V_{GE} = \pm 20\text{ V}$			$\pm 250$	nA

**Table 4. Dynamic characteristics**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{ies}$	Input capacitance	$V_{CE} = 25\text{ V}$ , $f = 1\text{ MHz}$ , $V_{GE} = 0\text{ V}$	-	2393	-	pF
$C_{oes}$	Output capacitance		-	146	-	pF
$C_{res}$	Reverse transfer capacitance		-	45.4	-	pF
$Q_g$	Total gate charge	$V_{CC} = 520\text{ V}$ , $I_C = 30\text{ A}$ , $V_{GE} = 0\text{ to }15\text{ V}$ (see Figure 26. Gate charge test circuit)	-	90	-	nC
$Q_{ge}$	Gate-emitter charge		-	16.5	-	nC
$Q_{gc}$	Gate-collector charge		-	39	-	nC

**Table 5. IGBT switching characteristics (inductive load)**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{CE} = 400\text{ V}$ , $I_C = 30\text{ A}$ , $V_{GE} = 15\text{ V}$ , $R_G = 10\ \Omega$ (see Figure 25. Test circuit for inductive load switching)		22	-	ns
$t_r$	Current rise time			10	-	ns
$di/dt_{(on)}$	Turn-on current slope			2350	-	A/ $\mu$ s
$t_{d(off)}$	Turn-off delay time			151	-	ns
$t_f$	Current fall time			152	-	ns
$E_{on}^{(1)}$	Turn-on switching energy			210	-	$\mu$ J
$E_{off}^{(2)}$	Turn-off switching energy			1147	-	$\mu$ J
$t_{d(on)}$	Turn-on delay time	$V_{CE} = 400\text{ V}$ , $I_C = 30\text{ A}$ , $V_{GE} = 15\text{ V}$ , $R_G = 10\ \Omega$ , $T_J = 175\text{ }^\circ\text{C}$ (see Figure 25. Test circuit for inductive load switching)		165	-	ns
$t_r$	Current rise time			11	-	ns
$di/dt_{(on)}$	Turn-on current slope			2120	-	A/ $\mu$ s
$t_{d(off)}$	Turn-off delay time			165	-	ns
$t_f$	Current fall time			238	-	ns
$E_{on}^{(1)}$	Turn-on switching energy			382	-	$\mu$ J
$E_{off}^{(2)}$	Turn-off switching energy			1530	-	$\mu$ J
$t_{sc}$	Short-circuit withstand time	$V_{CC} = 400\text{ V}$ , $V_{GE} = 15\text{ V}$ , starting $T_J \leq 150\text{ }^\circ\text{C}$	6		-	$\mu$ s

1. Including the reverse recovery of the diode.

2. Including the tail of the collector current.

**Table 6. Diode switching characteristics (inductive load)**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit	
$t_{rr}$	Reverse recovery time	$I_F = 30\text{ A}$ , $V_R = 400\text{ V}$ , $V_{GE} = 15\text{ V}$ , $di/dt = 1000\text{ A}/\mu\text{s}$ (see Figure 25. Test circuit for inductive load switching)	-	223	-	ns	
$Q_{rr}$	Reverse recovery charge			-	1.207	-	$\mu$ C
$I_{rrm}$	Reverse recovery current			-	16	-	A
$dI_{rr}/dt$	Peak rate of fall of reverse recovery current during $t_b$			-	90	-	A/ $\mu$ s
$E_{rr}$	Reverse recovery energy			-	0.265	-	mJ
$t_{rr}$	Reverse recovery time	$I_F = 30\text{ A}$ , $V_R = 400\text{ V}$ , $V_{GE} = 15\text{ V}$ , $di/dt = 1000\text{ A}/\mu\text{s}$ , $T_J = 175\text{ }^\circ\text{C}$ (see Figure 25. Test circuit for inductive load switching)	-	325	-	ns	
$Q_{rr}$	Reverse recovery charge			-	3.35	-	$\mu$ C
$I_{rrm}$	Reverse recovery current			-	25	-	A
$dI_{rr}/dt$	Peak rate of fall of reverse recovery current during $t_b$			-	450	-	A/ $\mu$ s
$E_{rr}$	Reverse recovery energy			-	0.845	-	mJ

## 2.1 Electrical characteristics (curves)

Figure 1. Total power dissipation vs temperature

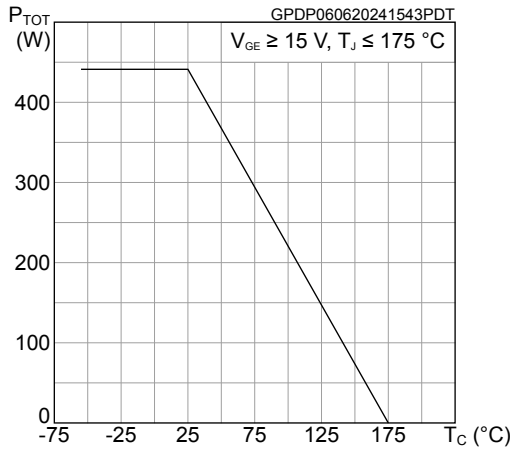


Figure 2. Collector current vs temperature

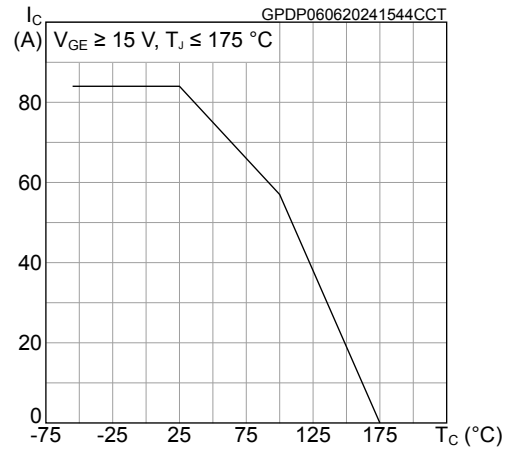


Figure 3. Typical output characteristics ( $T_J = 25\text{ °C}$ )

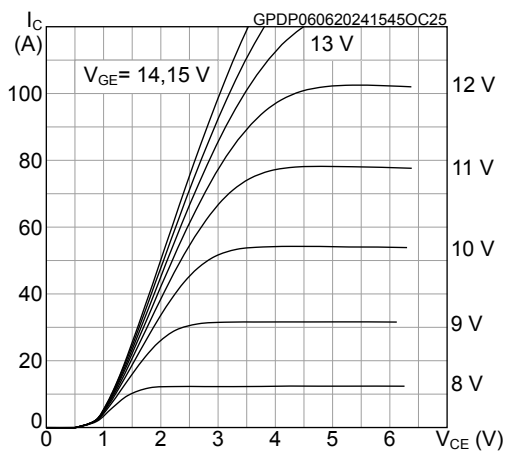


Figure 4. Typical output characteristics ( $T_J = 175\text{ °C}$ )

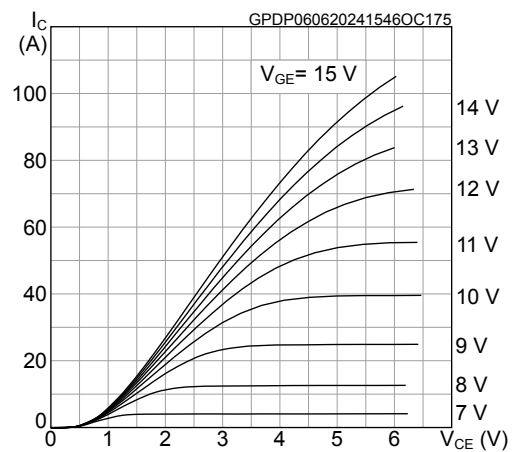


Figure 5. Typical transfer characteristics

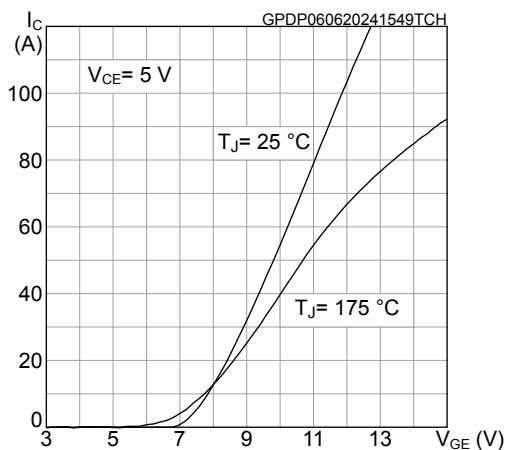
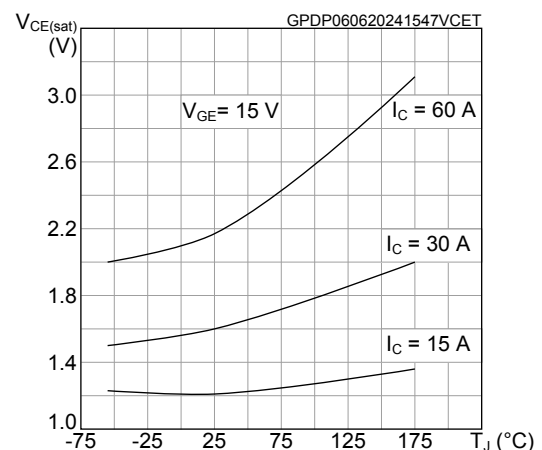
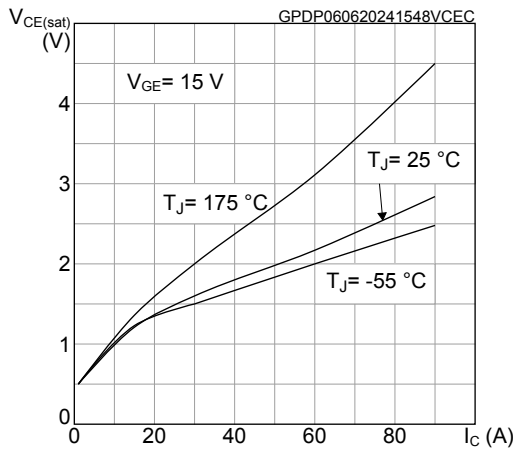


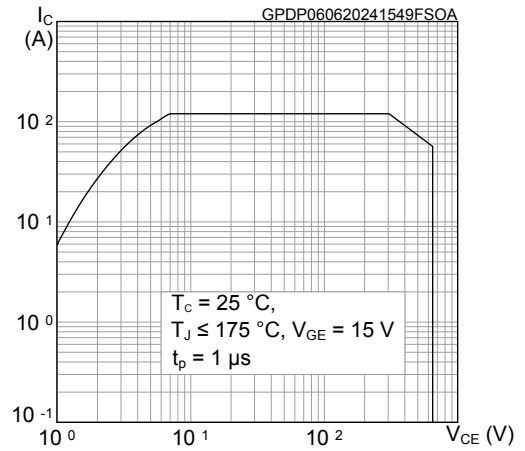
Figure 6. Typical  $V_{CE(sat)}$  vs temperature



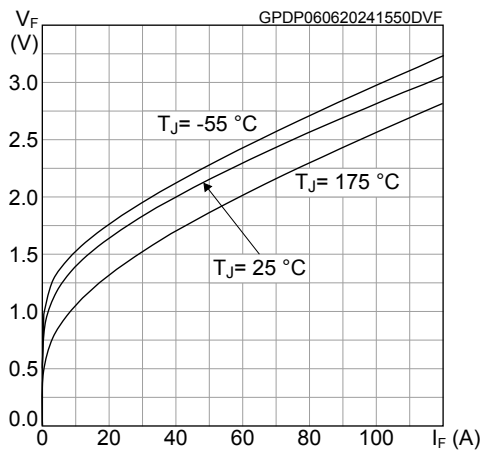
**Figure 7. Typical  $V_{CE(sat)}$  vs collector current**



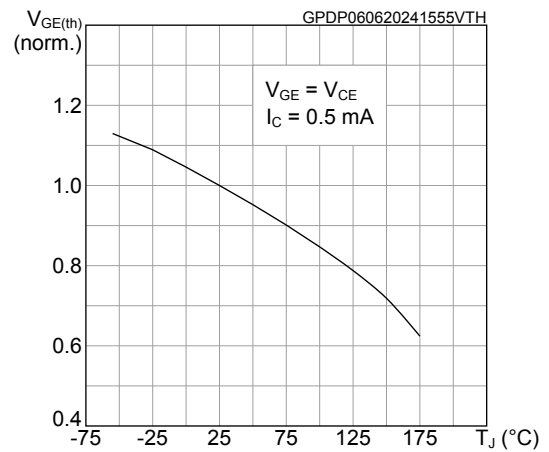
**Figure 8. Forward bias safe operating area**



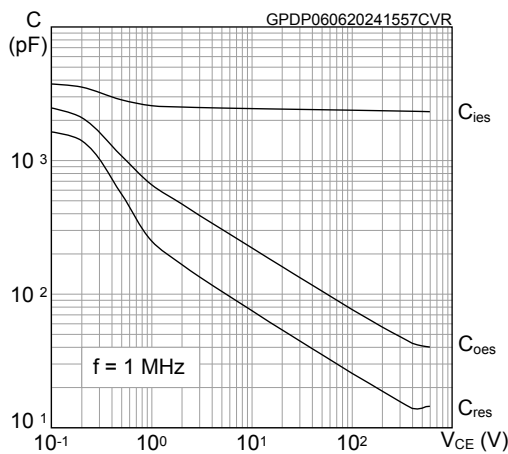
**Figure 9. Diode typical forward characteristics**



**Figure 10. Normalized gate threshold vs temperature**



**Figure 11. Typical capacitance characteristics**



**Figure 12. Typical gate charge characteristics**

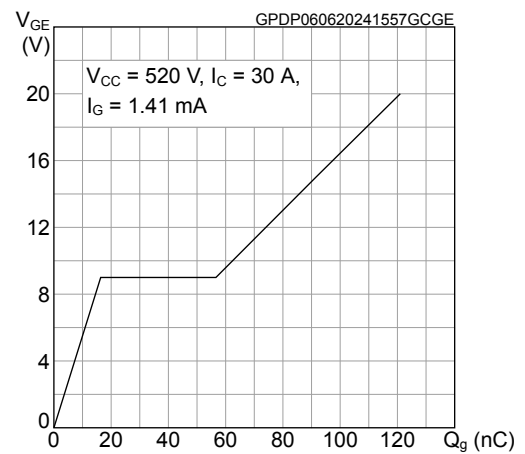


Figure 13. Typical switching energy vs collector current

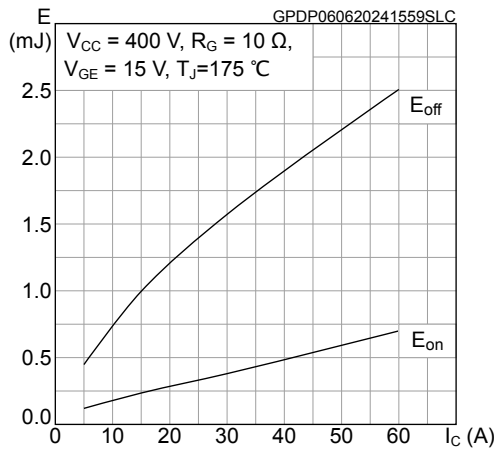


Figure 14. Typical switching energy vs temperature

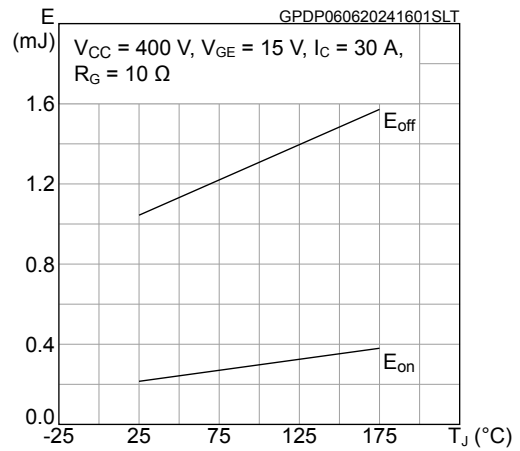


Figure 15. Typical switching energy vs supply voltage

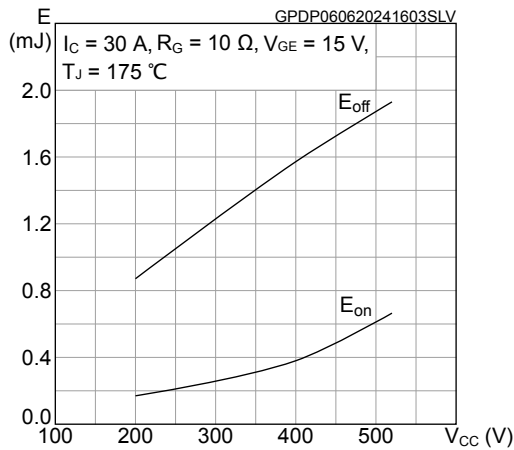


Figure 16. Typical switching energy vs gate resistance

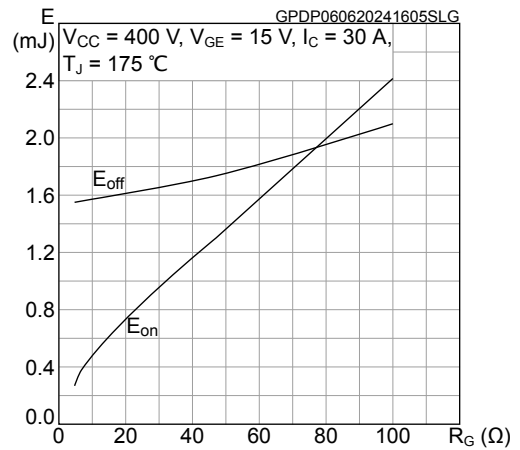


Figure 17. Typical switching times vs collector current

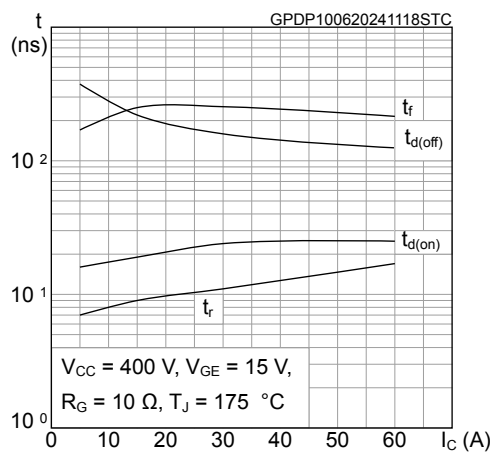


Figure 18. Typical switching times vs gate resistance

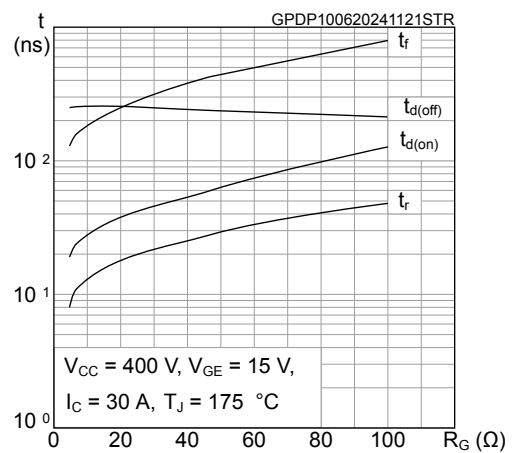


Figure 19. Typical reverse recovery current vs diode current slope

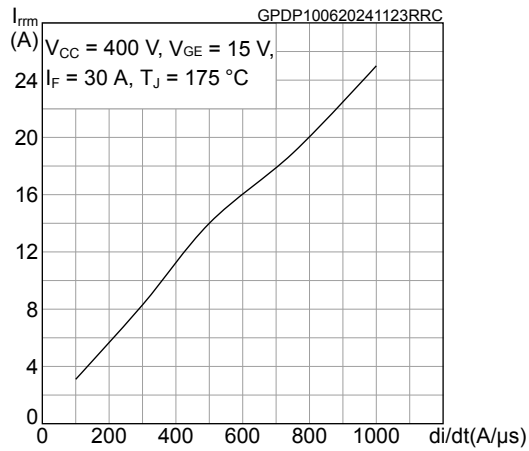


Figure 20. Typical reverse recovery time vs diode current slope

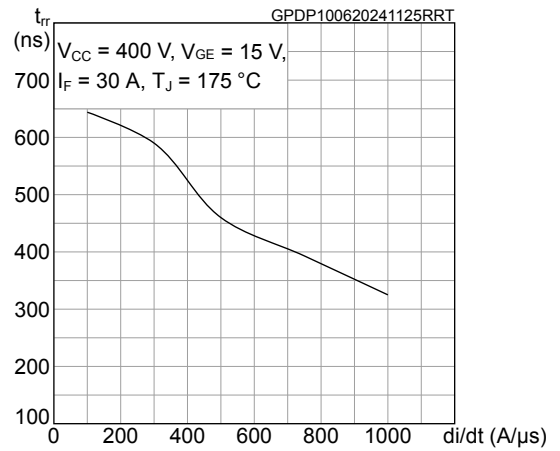


Figure 21. Typical reverse recovery charge vs diode current slope

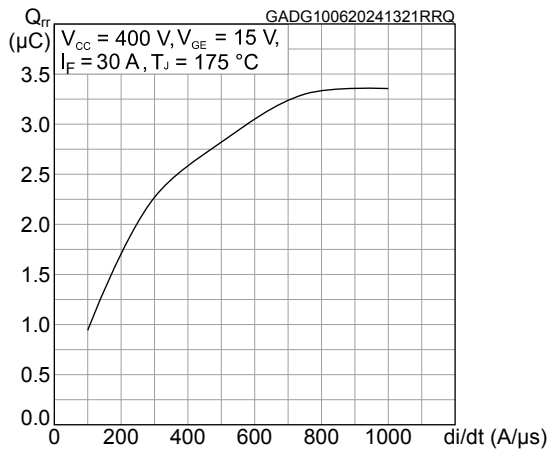


Figure 22. Typical reverse recovery energy vs diode current slope

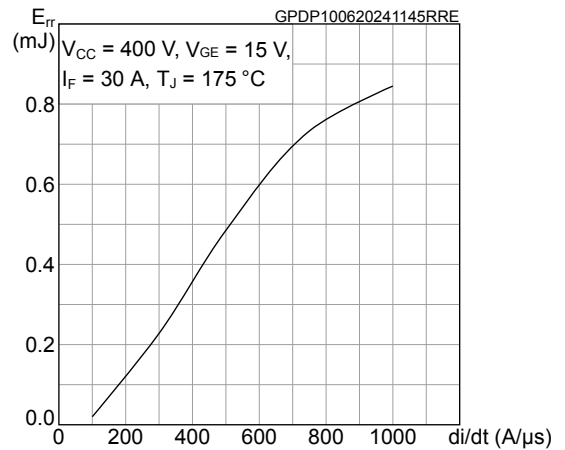


Figure 23. IGBT maximum transient thermal impedance

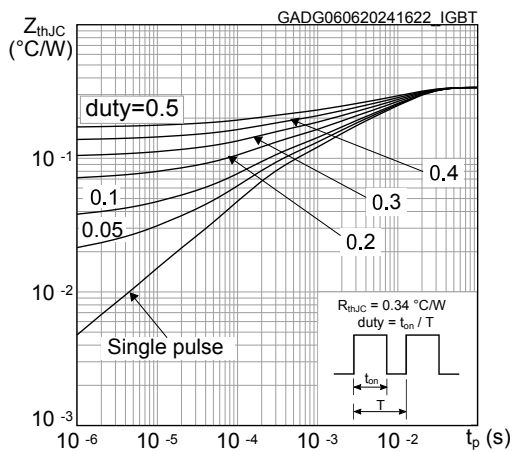
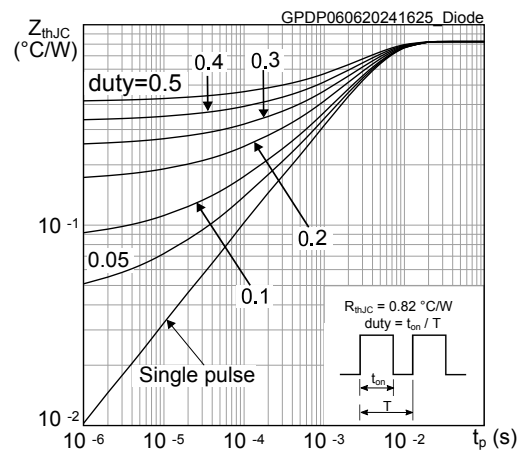


Figure 24. Diode maximum transient thermal impedance





### 3 Test circuits

Figure 25. Test circuit for inductive load switching

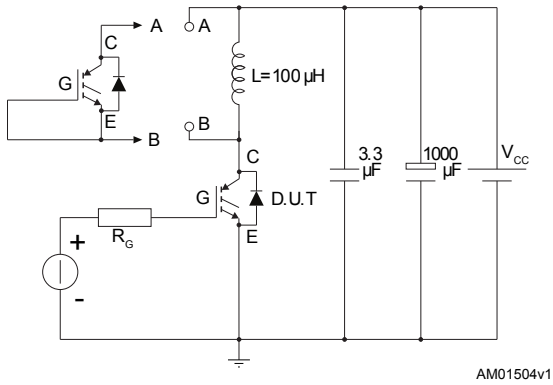


Figure 26. Gate charge test circuit

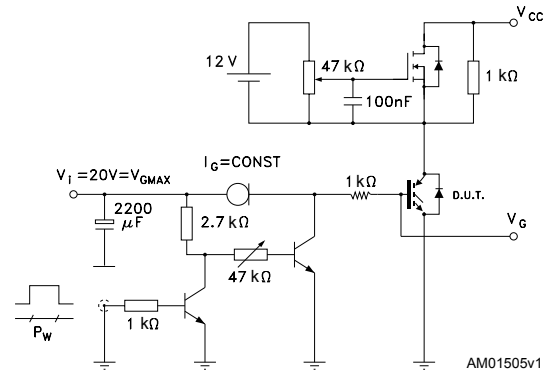


Figure 27. Switching waveform

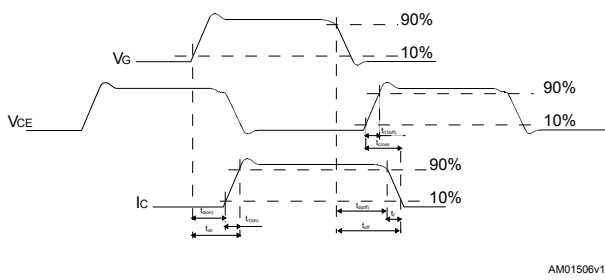
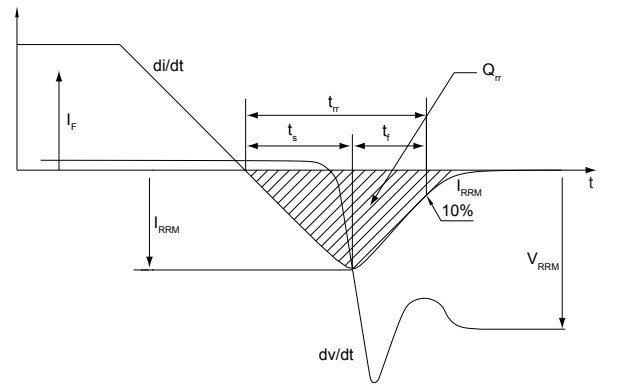


Figure 28. Diode reverse recovery waveform

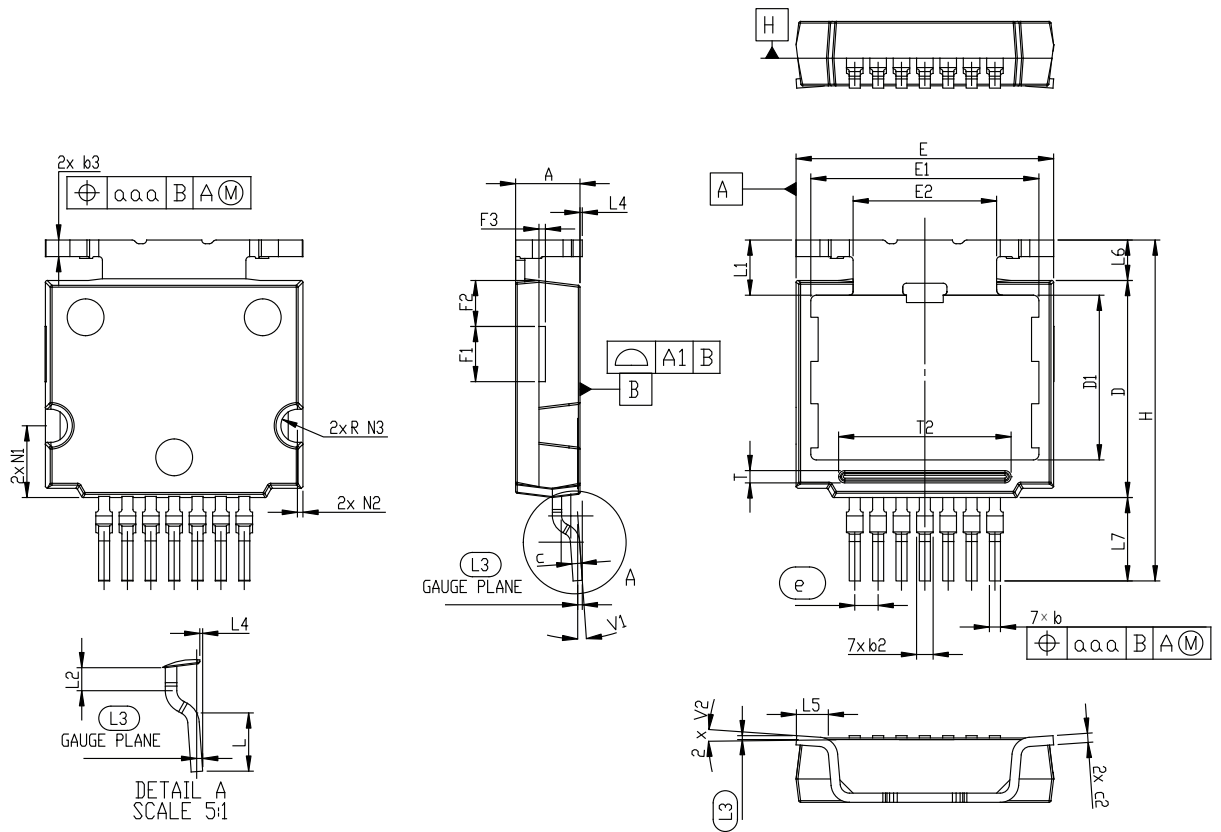


## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of **ECOPACK** packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

### 4.1 HU3PAK package information

Figure 29. HU3PAK package outline

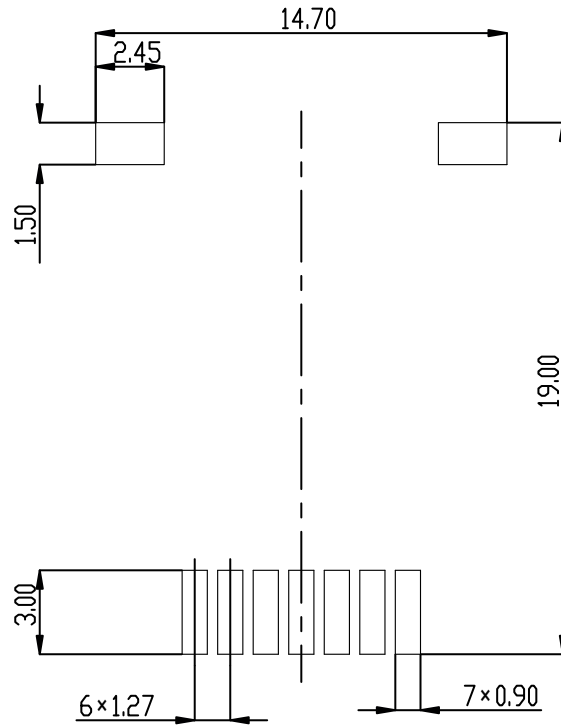


DM00674007\_2

**Table 7. HU3PAK package mechanical data**

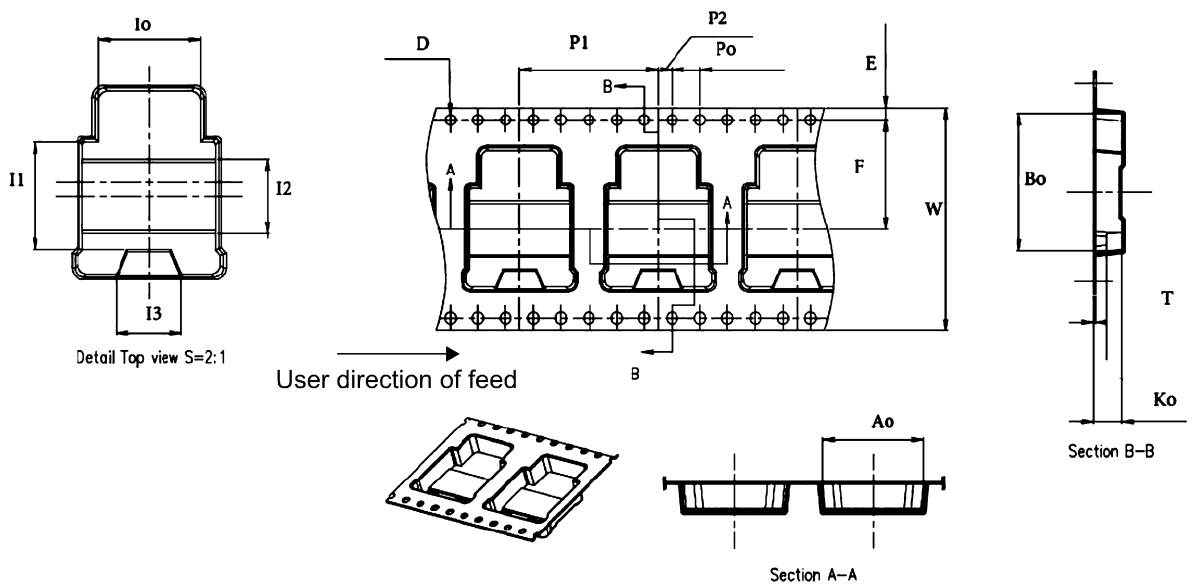
Ref.	Dimensions		
	mm		
	Min.	Typ.	Max.
A	3.40	3.50	3.60
A1		0.05	
b	0.50	0.60	0.70
b2	0.50	0.70	1.00
b3	0.80	0.90	1.00
c	0.40	0.50	0.60
c2	0.40	0.50	0.60
D	11.70	11.80	11.90
D1	8.80	8.955	9.10
E	13.90	14.00	14.10
E1	12.30	12.40	12.50
E2	7.75	7.80	7.85
e		1.27	
H	18.00	18.58	19.00
aaa		0.10	
L	2.40	2.52	2.60
L1		3.05	
L2	0.90	1.00	1.10
L3		0.26	
L4	0.075	0.125	0.175
L5	1.83	1.93	2.03
L6	2.14	2.24	2.34
L7	4.44	4.54	4.64
F1	2.90	3.00	3.10
F2	2.40	2.50	2.60
F3	0.25	0.35	0.45
N1	3.80	3.90	4.00
N2	0.25	0.30	0.45
N3	0.80	0.90	1.00
T	0.50	0.67	0.70
T2	9.18	9.38	9.43
V1		0°	8°
V2		0°	8°

Figure 30. HU3PAK recommended footprint (dimensions in mm)



## 4.2 HU3PAK packing information

Figure 31. HU3PAK carrier tape outline



DM00345054\_3



## Revision history

Table 9. Document revision history

Date	Revision	Changes
11-Jun-2024	1	First release.

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